





Power Accelerated

Next-generation GaN Isolators / Level-Shifters for High Frequency, High Efficiency Power Conversion

PSMA Industry Session, Isolation Barrier Technologies for Power Electronics

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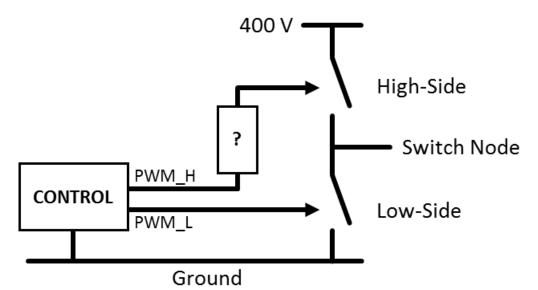
APEC, March 30th 2017

Navitas GaN Power IC Navitas GaN Power



Scope: The Half-Bridge Challenge

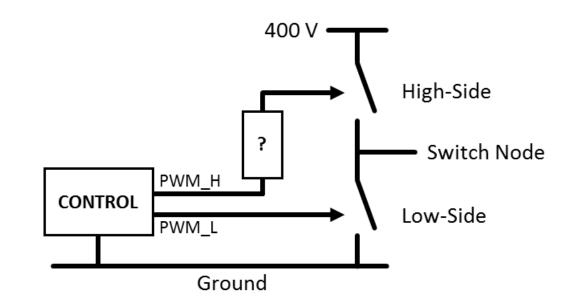
- Half-Bridge Topologies:
 - Active Clamp Flyback (25-65W)
 - LLC (90-400W+)
- Switching Frequency 100 kHz 1 MHz+
- Functional (not galvanic) isolation (650 V)
- Function (uni-directional)
 - High-side Power
 - High-side Signal
- Normalized to 160 m Ω , 2.5 nC Q_G , eMode GaN FETs
 - Focus on driver, level-shifter influence





Level-Shift Performance → System Size, Cost

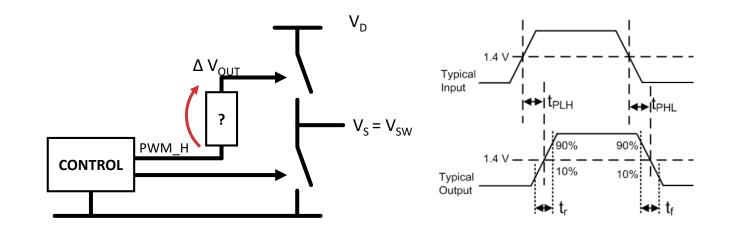
- Efficiency
 - Level-shift (driver) loss
 - Propagation delay loss
- Speed
 - Propagation delay
 - Switching frequency
- Noise
 - Common Mode Transient Immunity (CMTI) (dV/dt)
- Features
 - Protection (shoot-through, ESD, UVLO, etc.)
 - Programmability
- Cost
 - Integration, component count, magnetics size



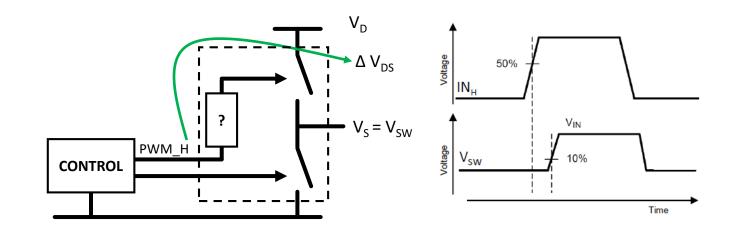


A Note on Prop Delay

- Traditional 'discrete' level-shifter
 - Measured from the incoming PWM_H signal to a 10% change in the level-shifter's own output
 - No account for FET speed, R_G, Z_G, etc.

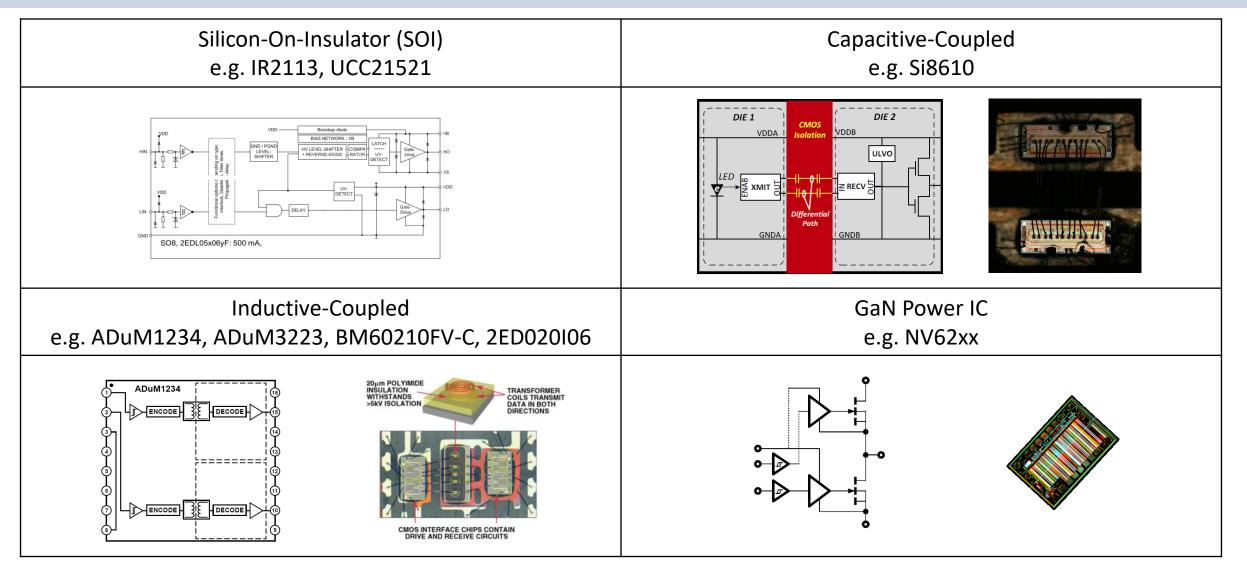


- Integrated GaN Power IC
 - Measured from PWM_H signal to a 10% change in high-side FET V_{DS}
 - Complete accountability



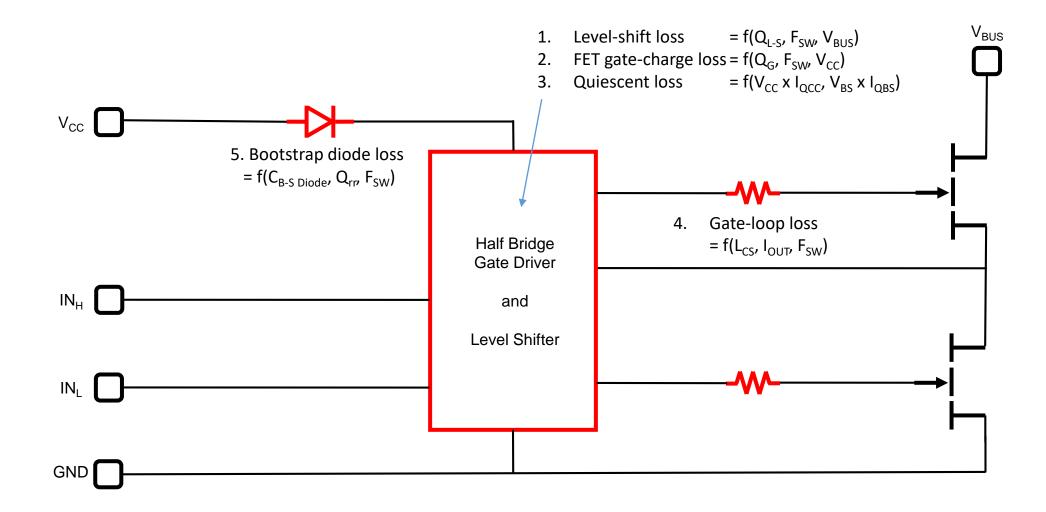


High-Frequency Level-Shift Candidates





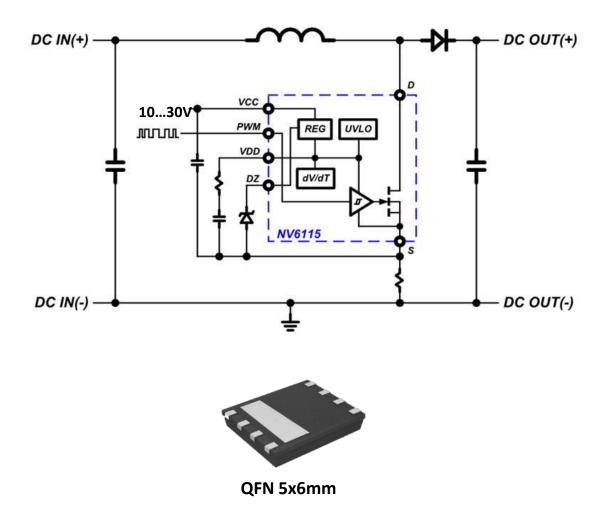
Discrete Half-Bridge Drive: 5 Losses





Start with the single GaN Power IC

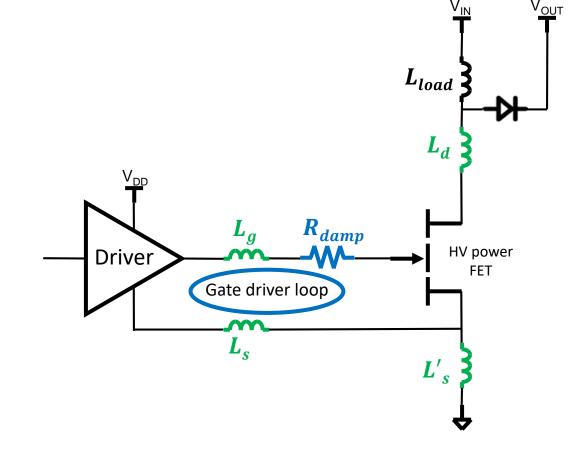
- Proprietary AllGaN[™] technology
- Monolithic integration
- 650 V, eMode, GaN FET, GaN driver, GaN logic
- Very fast (prop delay and turn-on/off of 10-20 ns)
- High dV/dt immunity (200 V/ns) with control
- Digital in, power out...





Gate-Loop Loss = $fn(L_{CS}, I_{OUT}, F_{SW})$

- Common source inductance loss
- Damping resistor needed to reduce oscillation, voltage spike at the FET gate



 $R_{damp} \ge \sqrt{\frac{4(Lg + Ls)}{C_{gs}}}$

L _g +L _s [nH]	R _{damp} [Ω]
0	0
1	2.83
2	4
3	4.9
4	5.66

Cgs = 500pF



-1.0

- 9.0

- 7.0

-5.0

- 3.0

-1.0

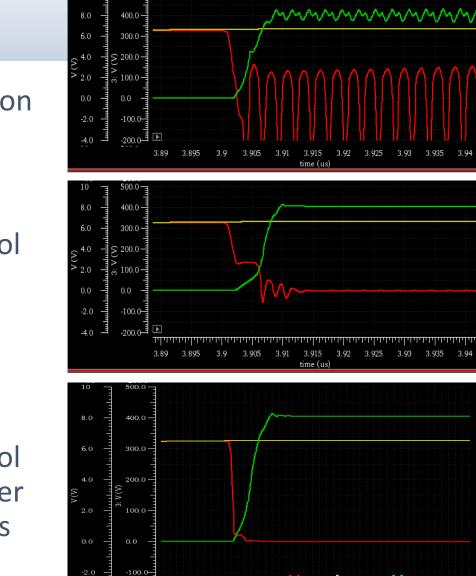
3.936

Integration is Key

1. External driver:



- 2. External driver + R_G :
- In control Slow Lossy



3.898

3.906

time (us

3.922

3.93

500.0-

3. Integrated driver:

In control 10x faster Zero loss

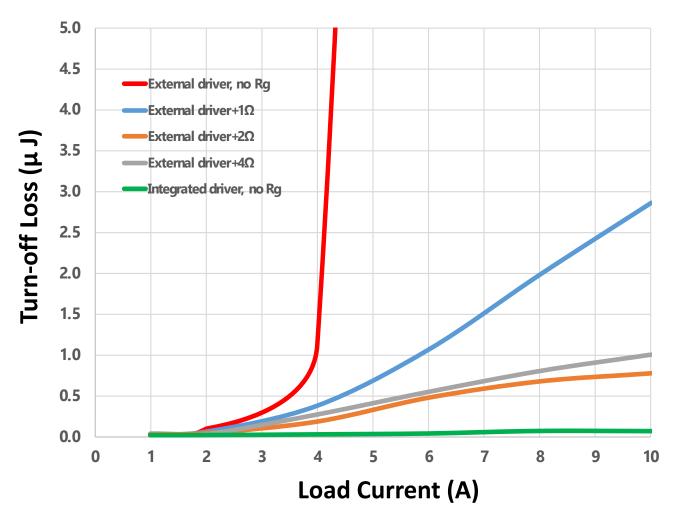
Speed & Integration -> Eliminate Turn-off Losses

External drivers

- Significant turn-off losses
- Just 1-2 nH of gate loop inductance can cause voltage spikes that create unintended turn-on of the GaN FET
- Adding a gate resistor reduces spikes but slows down the circuit creating additional losses

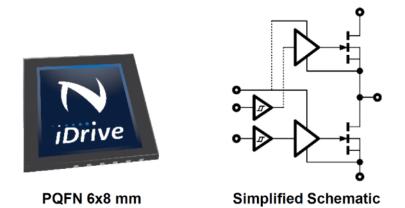
Integrated GaN drivers (iDrive™)

- Eliminate the problem
- Negligible turn-off losses

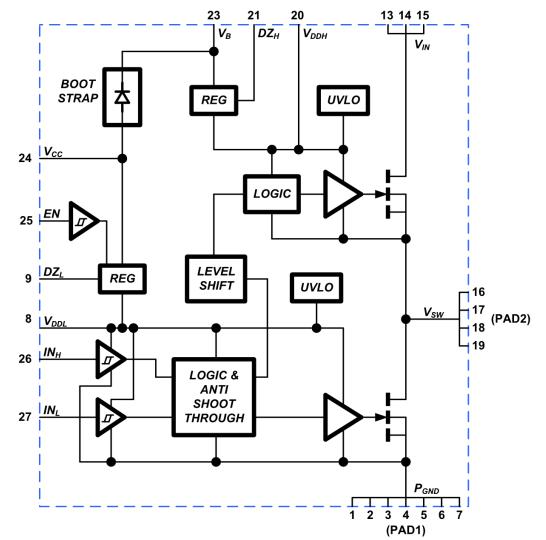




Half-Bridge iDrive GaN Power IC

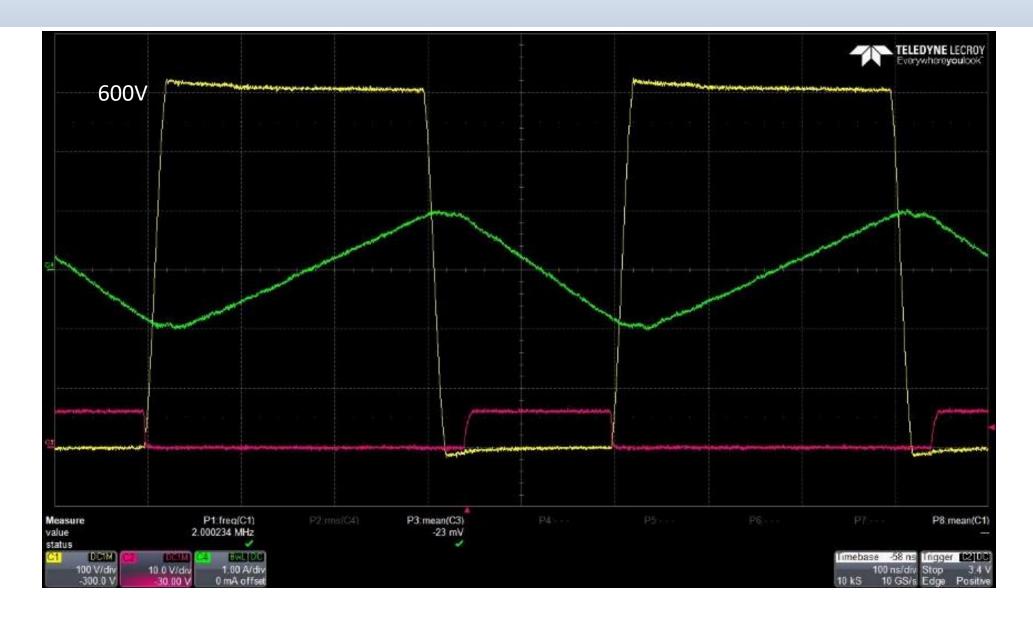


- Proprietary AllGaN[™] technology
- Monolithic integration of 650V eMode GaN FET, driver, logic
- Internal level-shift, bootstrap
- Ground-referenced, digital input
- High dV/dt immunity (200 V/ns)
- Zero inductance turn-off loops
- Very fast (prop delay and turn-on/off of 20-40 ns)
- ESD, UVLO, shoot-through protection
- Flexible topologies: Active Clamp Flyback, Half-Bridge, LLC, etc.





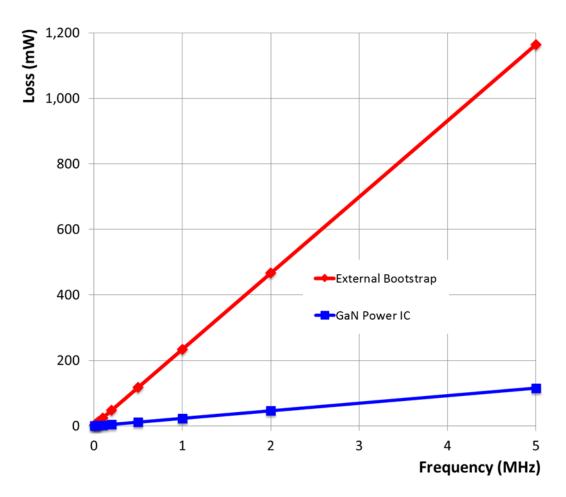
Half-Bridge GaN Power IC at 2 MHz



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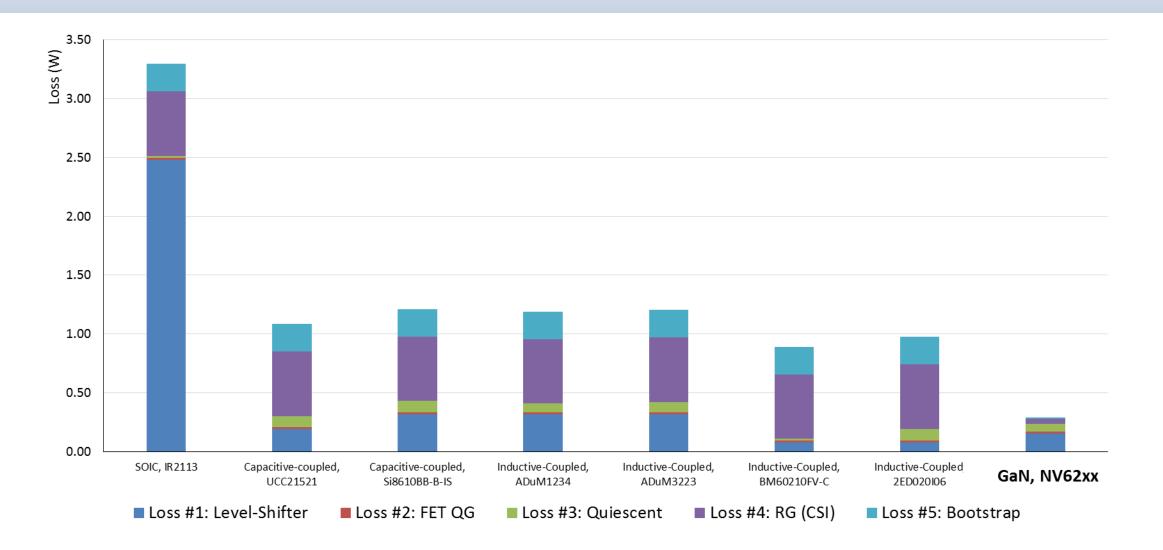


Bootstrap Diode Loss = fn(C_{B-S Diode}, Q_{rr}, F_{SW})





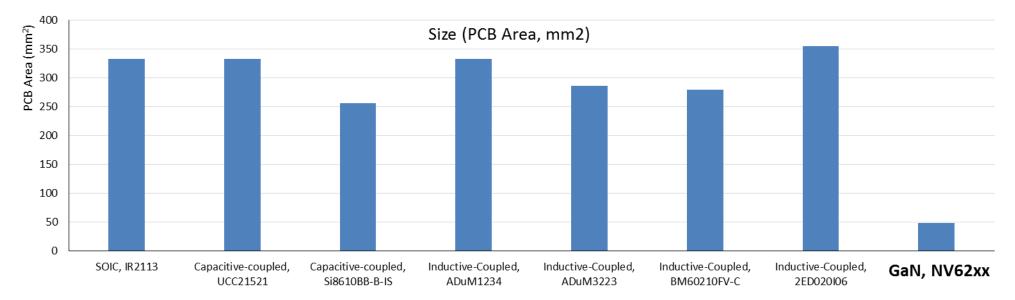
3x Lower Level-Shift Total Loss at 1 MHz





5x Smaller, Easier

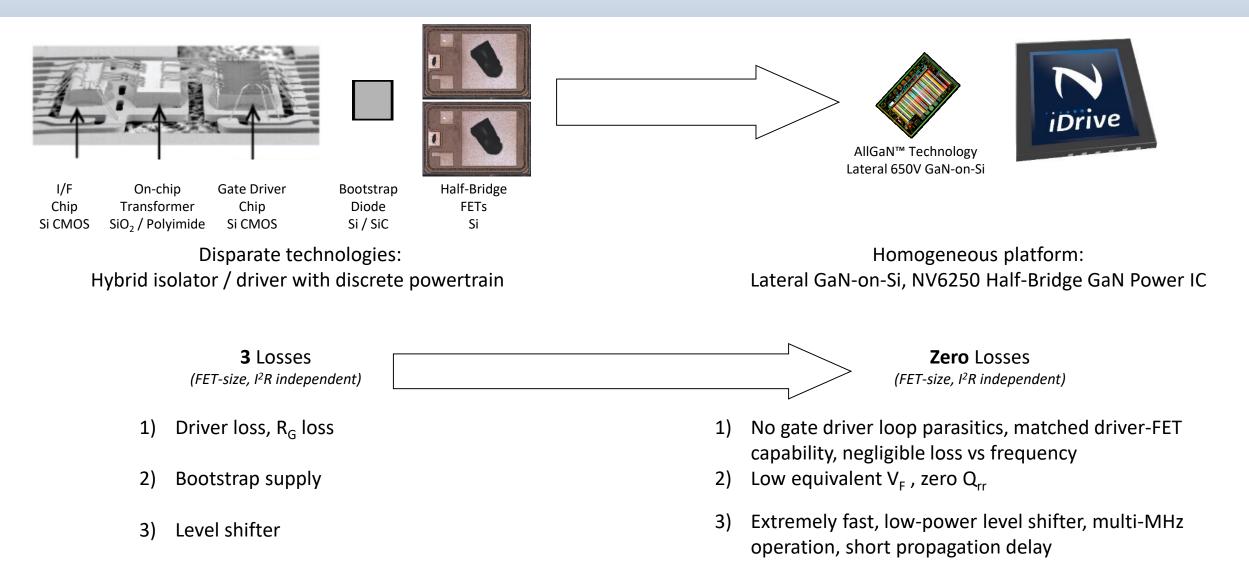
5 NV62xx



Si8610 + 2x FETs + Bootstrap + Rs, Cs

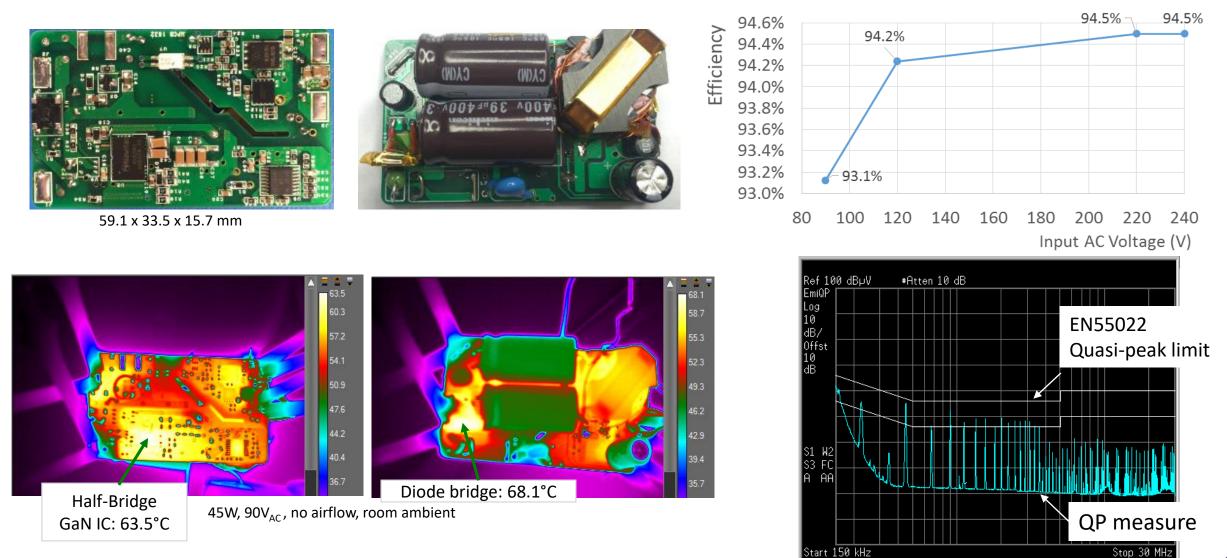


High-Frequency Half-Bridge Integration





45W Adapter – 25 W/in³



es BW 9 kHz

VBW 30 kHz

Sweep 4 ks (1515 pts)





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Additional APEC references:

Paper ID#1104, State-of-the-Art Mobile Charging: Topologies, Technologies and Performance, Tom Ribarich and Stephen Oliver (Navitas) Paper ID#2158, Active Clamp Flyback Using GaN Power IC for Power Adapter Applications, Lingxiao Xue and Jason Zhang (Navitas) Paper ID#1159, GaN Power ICs at 1 MHz+: Topologies, Technologies and Performance, Dan Kinzer (Navitas) Paper ID#1117, Next-Generation GaN Isolators for High Frequency, High Efficiency Power Conversion, Stephen Oliver, Marco Giandalia (Navitas)